

FIG. 1A
PRIOR ART

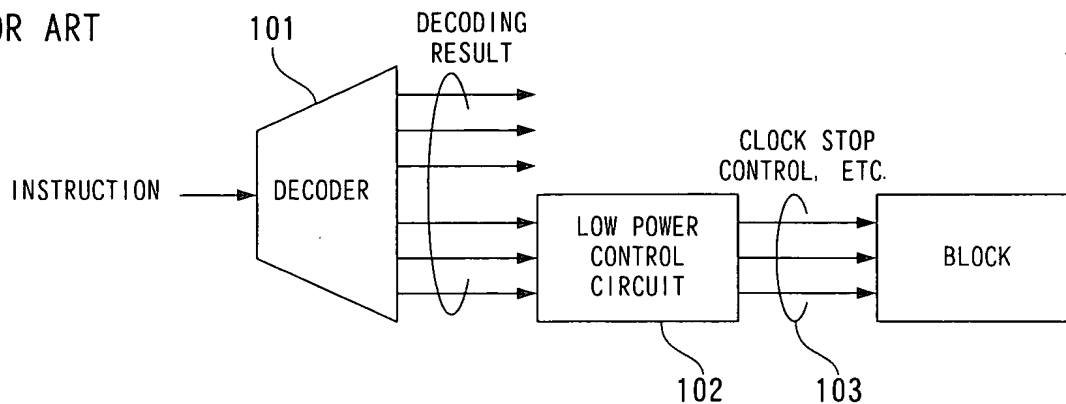


FIG. 1B
PRIOR ART

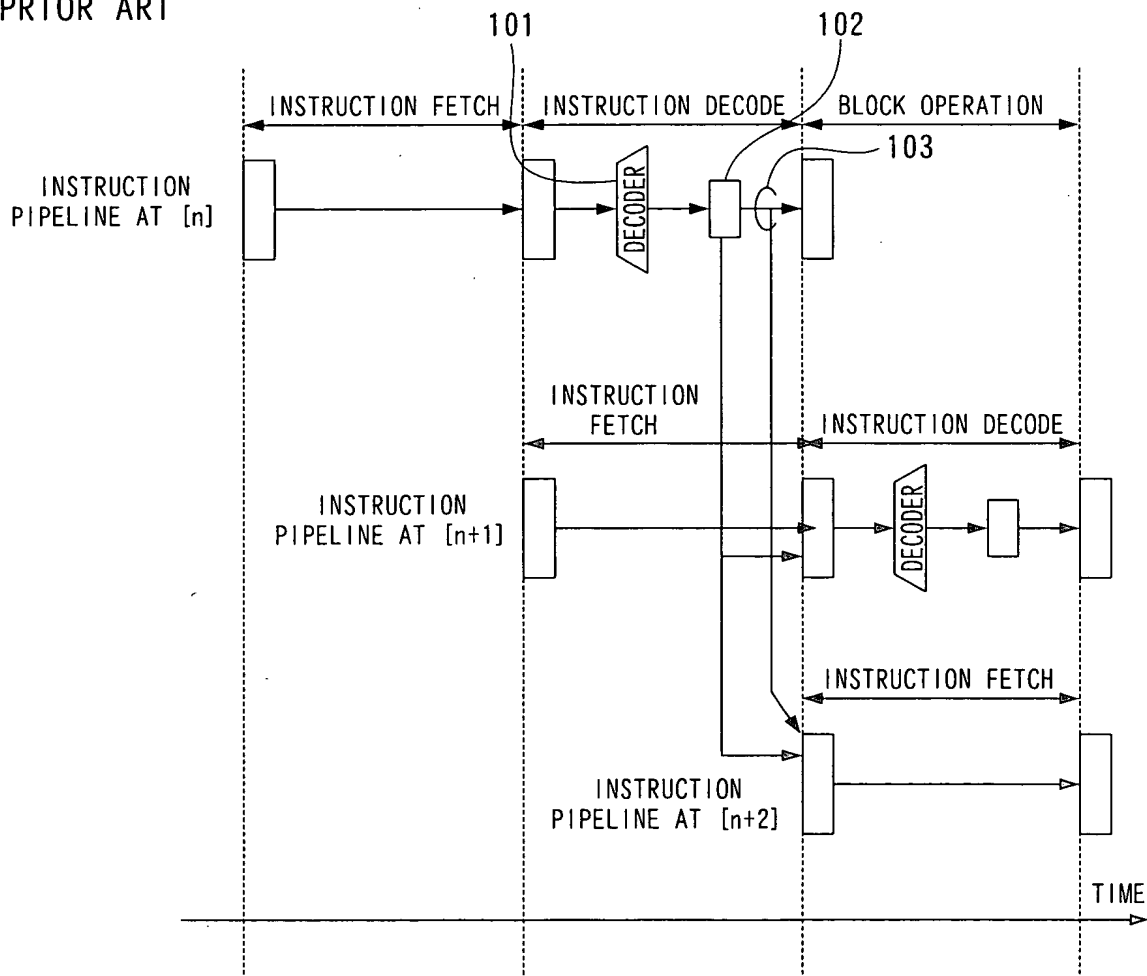


FIG. 2A
PRIOR ART

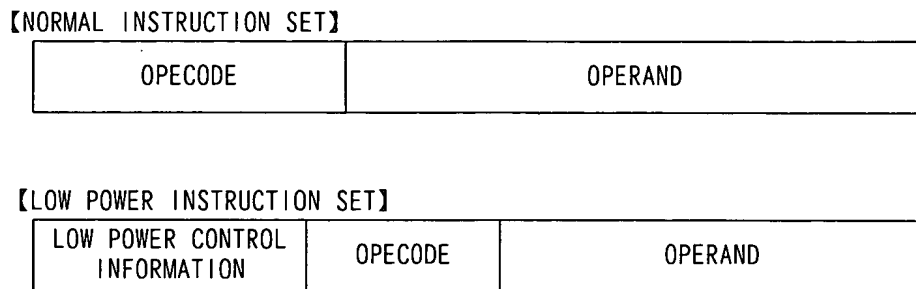


FIG. 2B
PRIOR ART

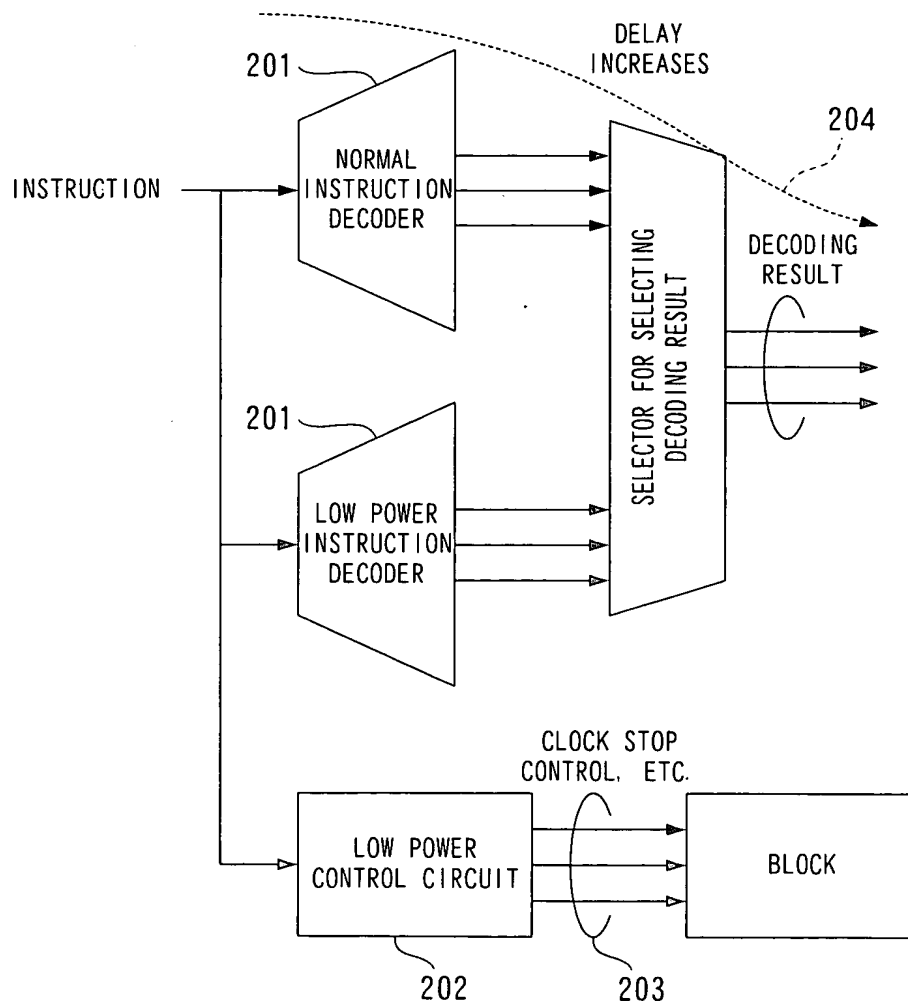


FIG. 3
PRIOR ART

※1: SET CONTROL INFORMATION OF
PRECEDING INSTRUCTION
(SETTING AT [n+2] IN THIS
DIAGRAM)

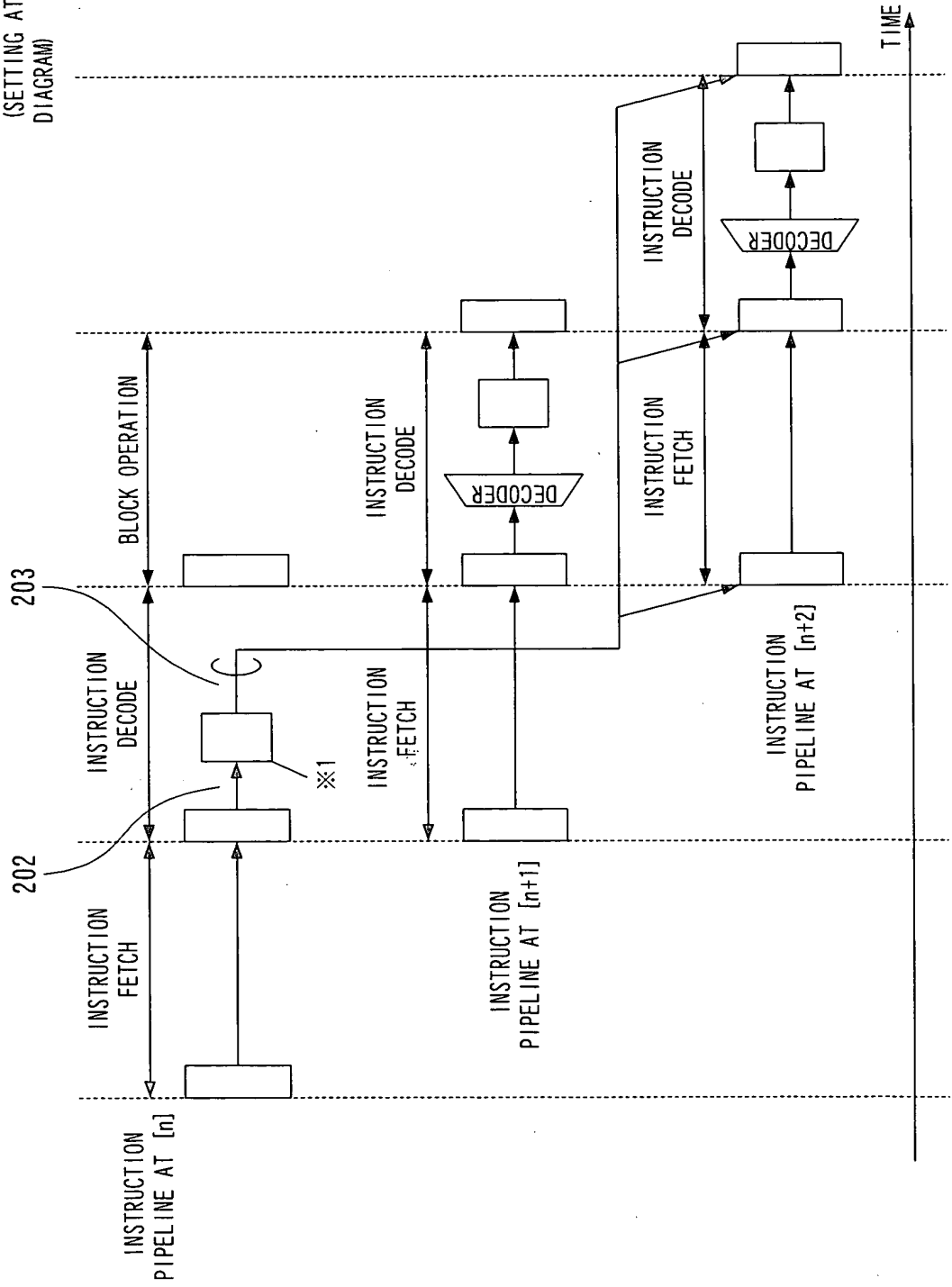


FIG. 4A

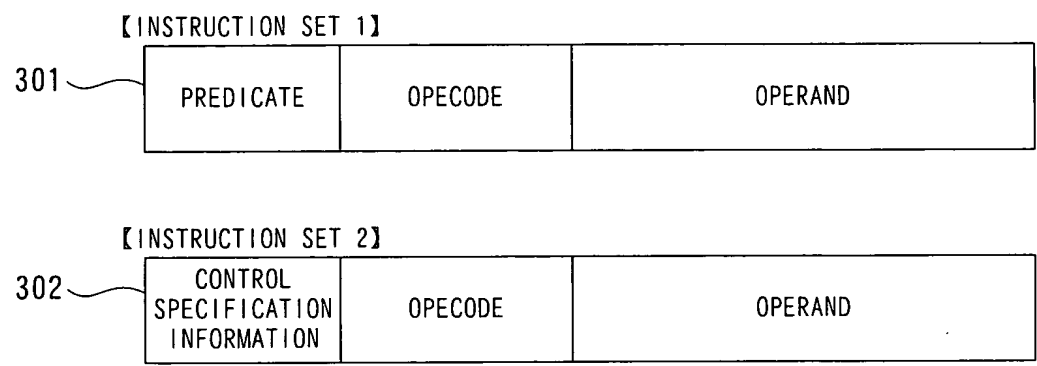
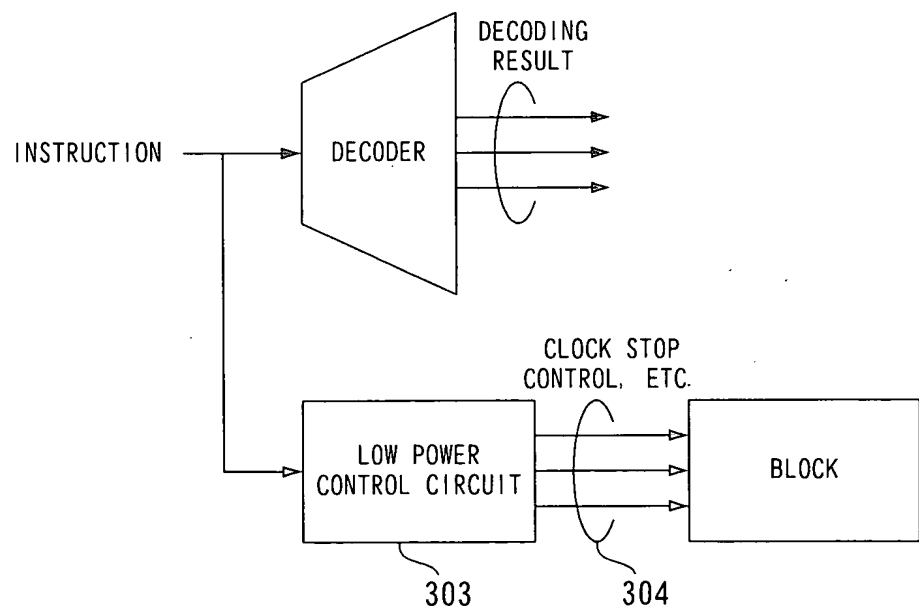


FIG. 4B



※1: SET CONTROL INFORMATION OF
PRECEDING INSTRUCTION
(SETTING AT [n+2] IN THIS
DIAGRAM)

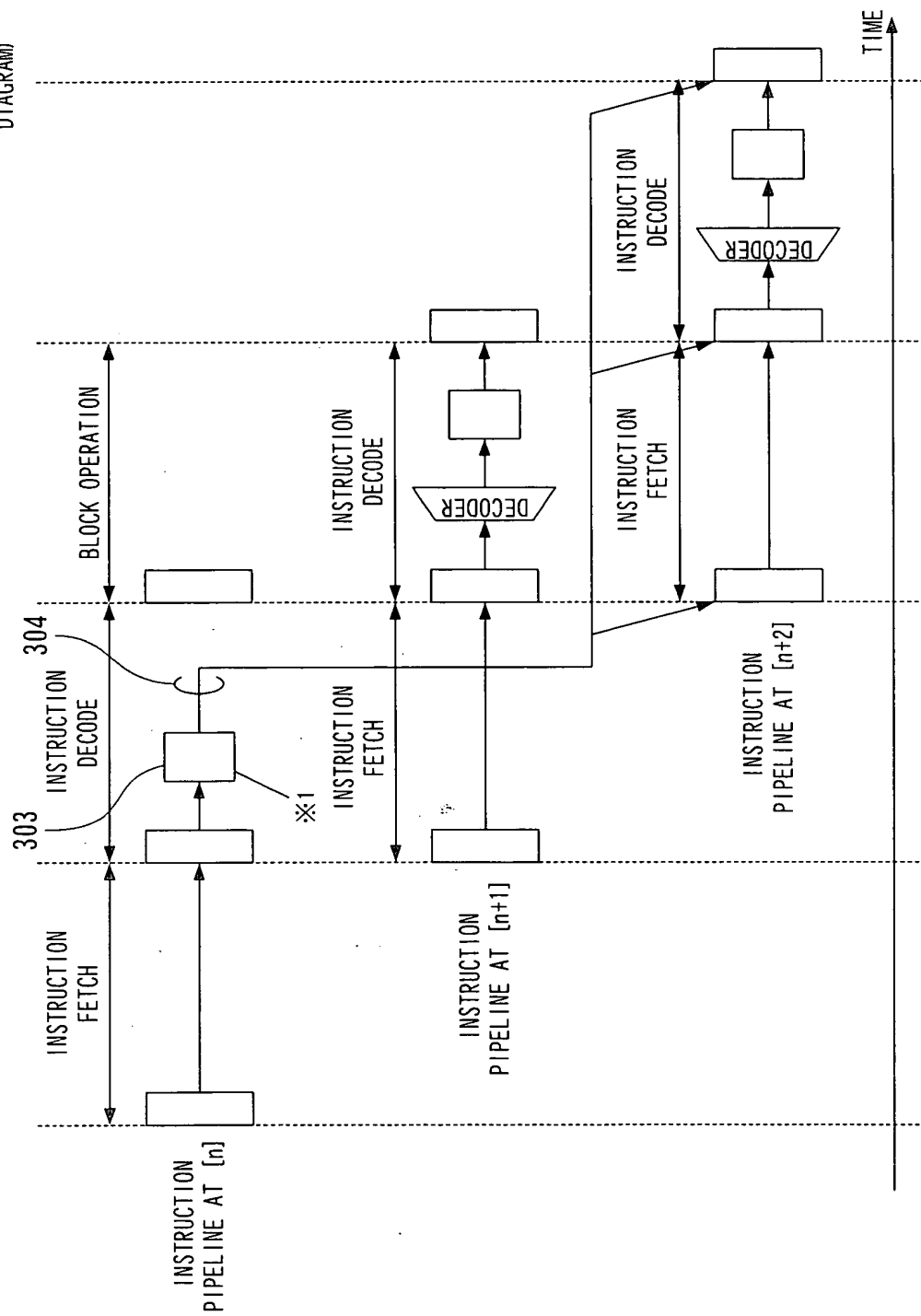


FIG. 6

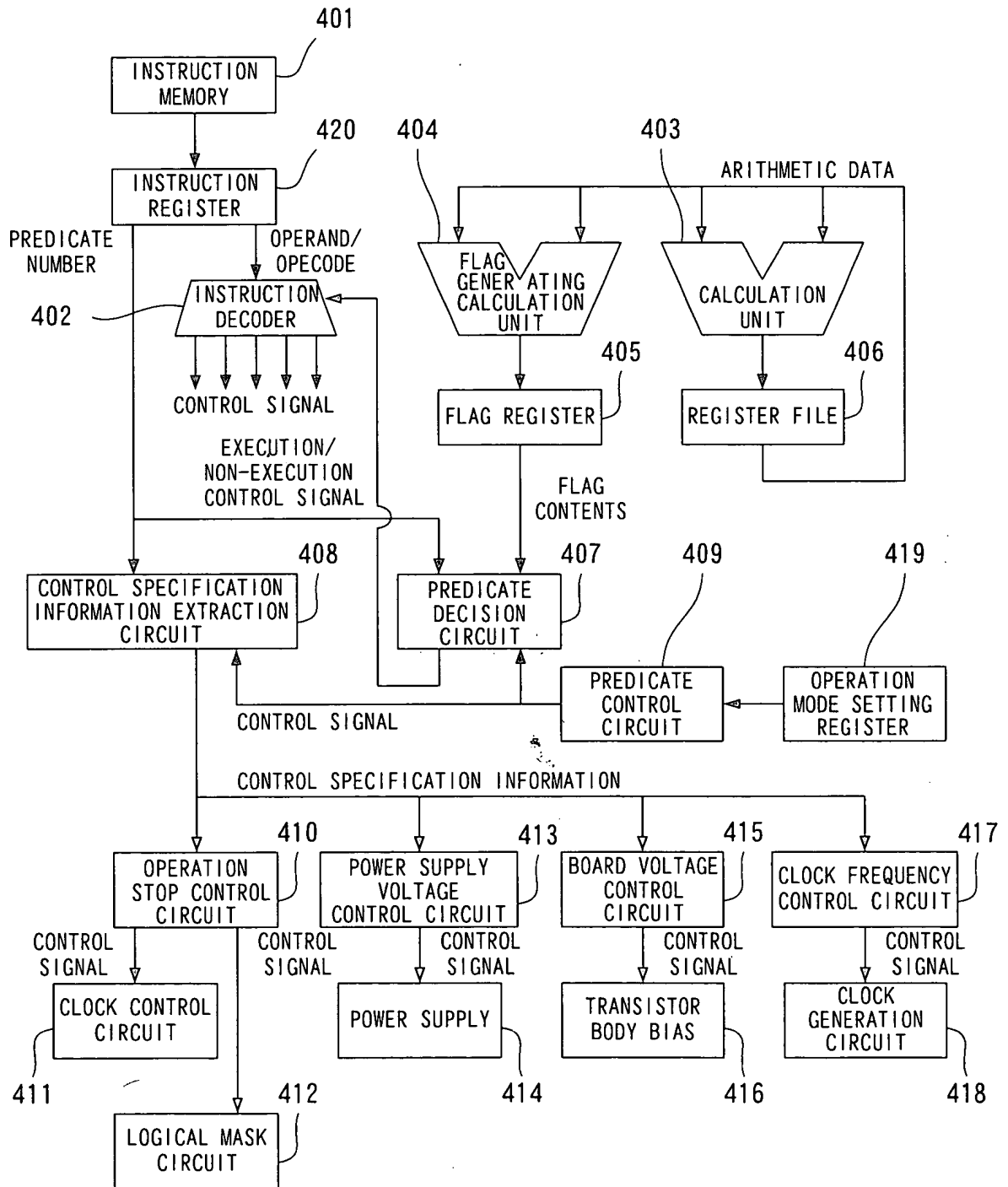


FIG. 7

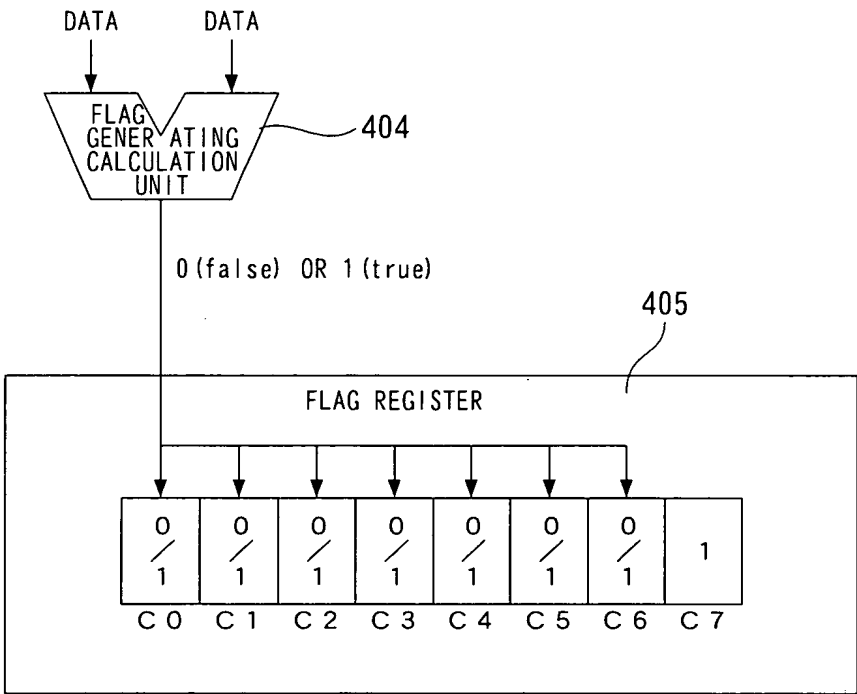


FIG. 8

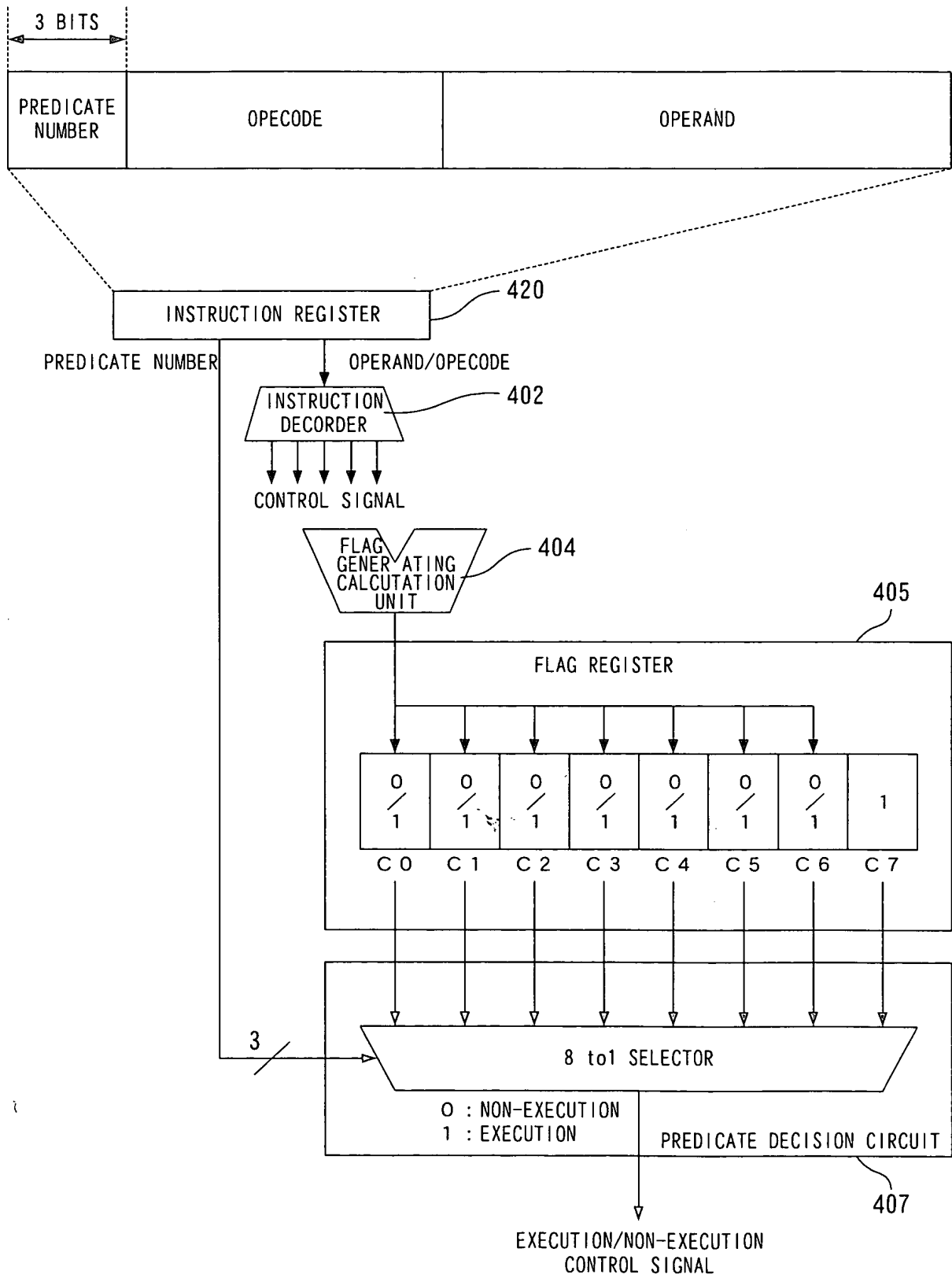


FIG. 9

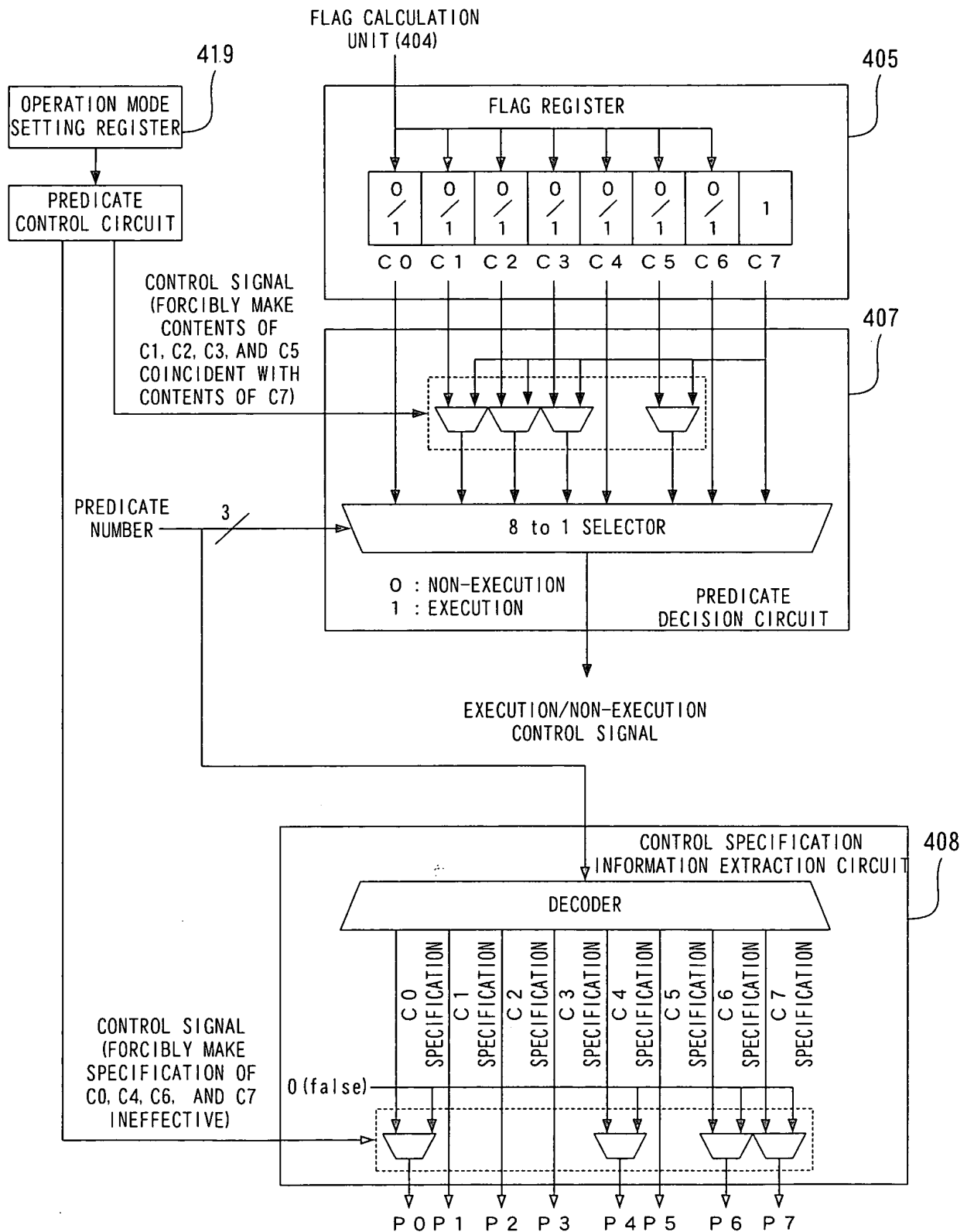


FIG. 10

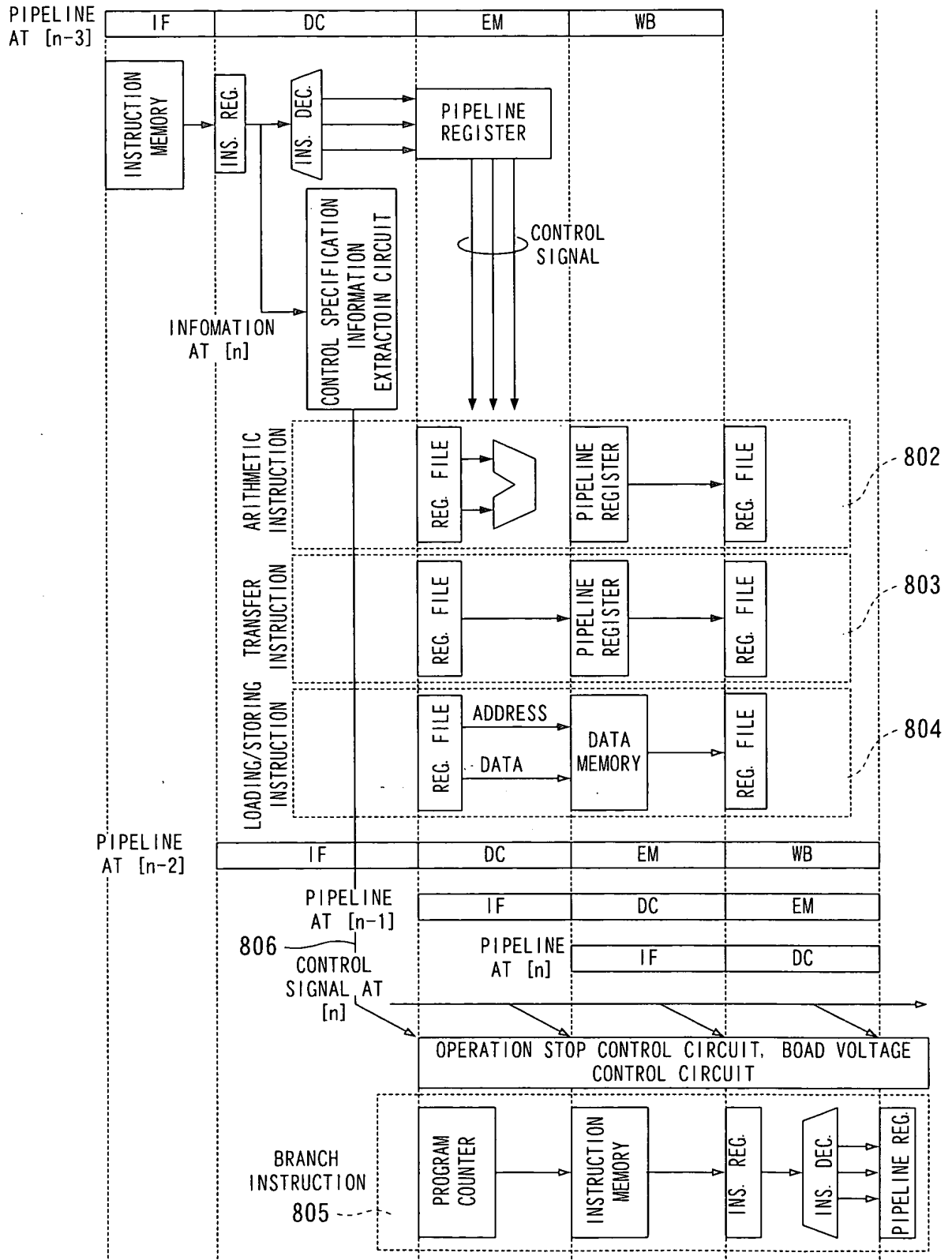


FIG. 11

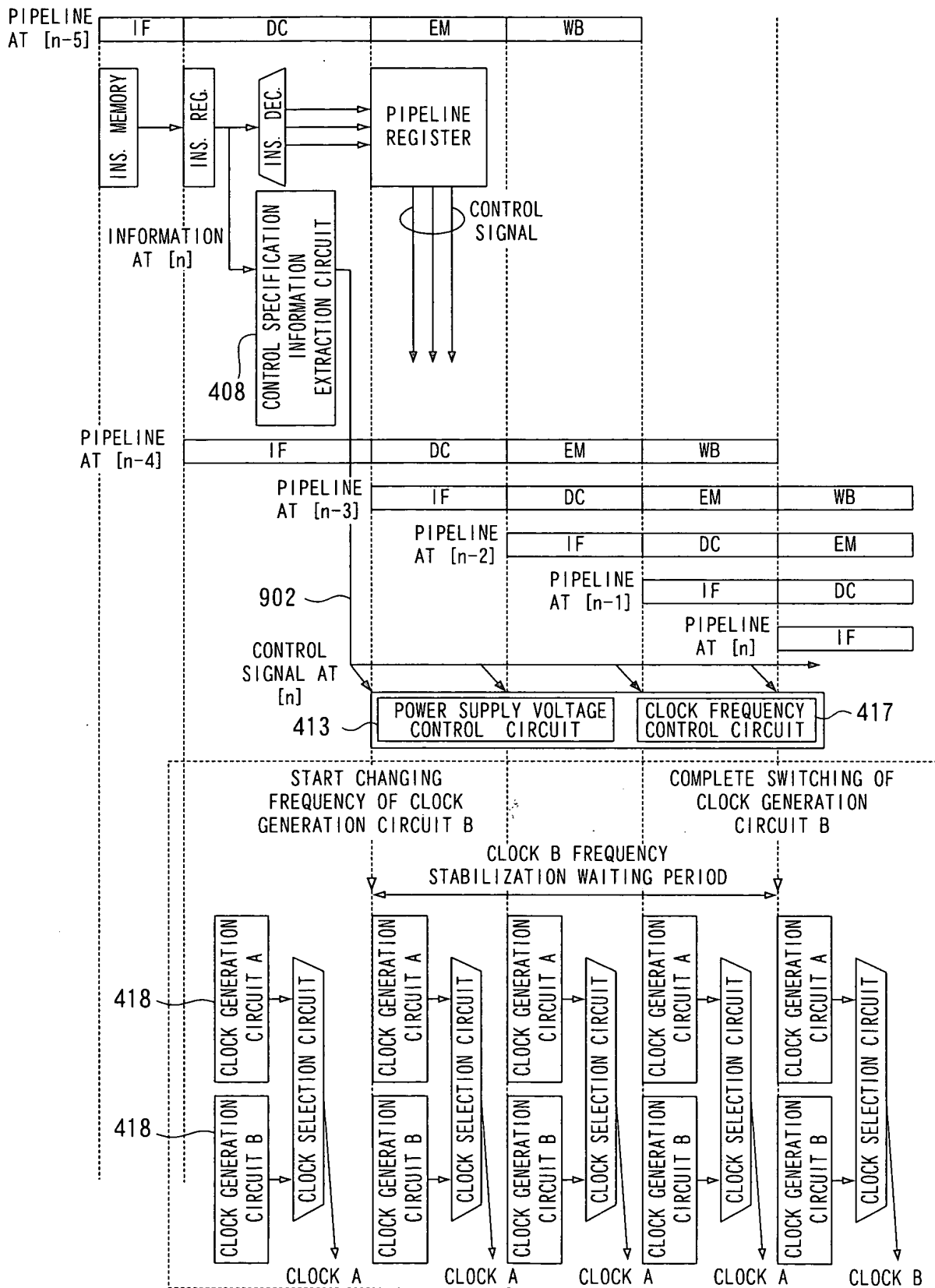


FIG. 12

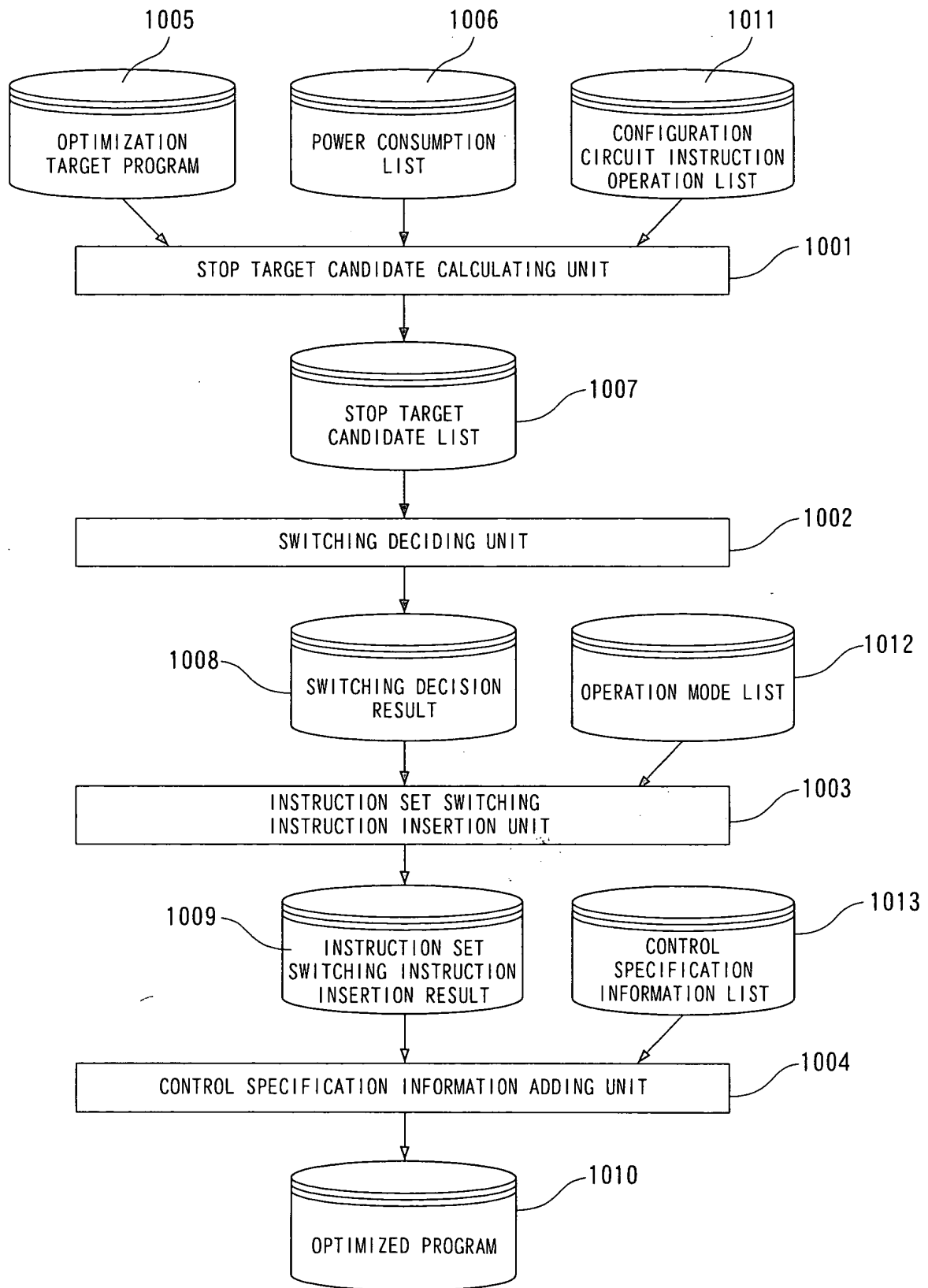


FIG. 13

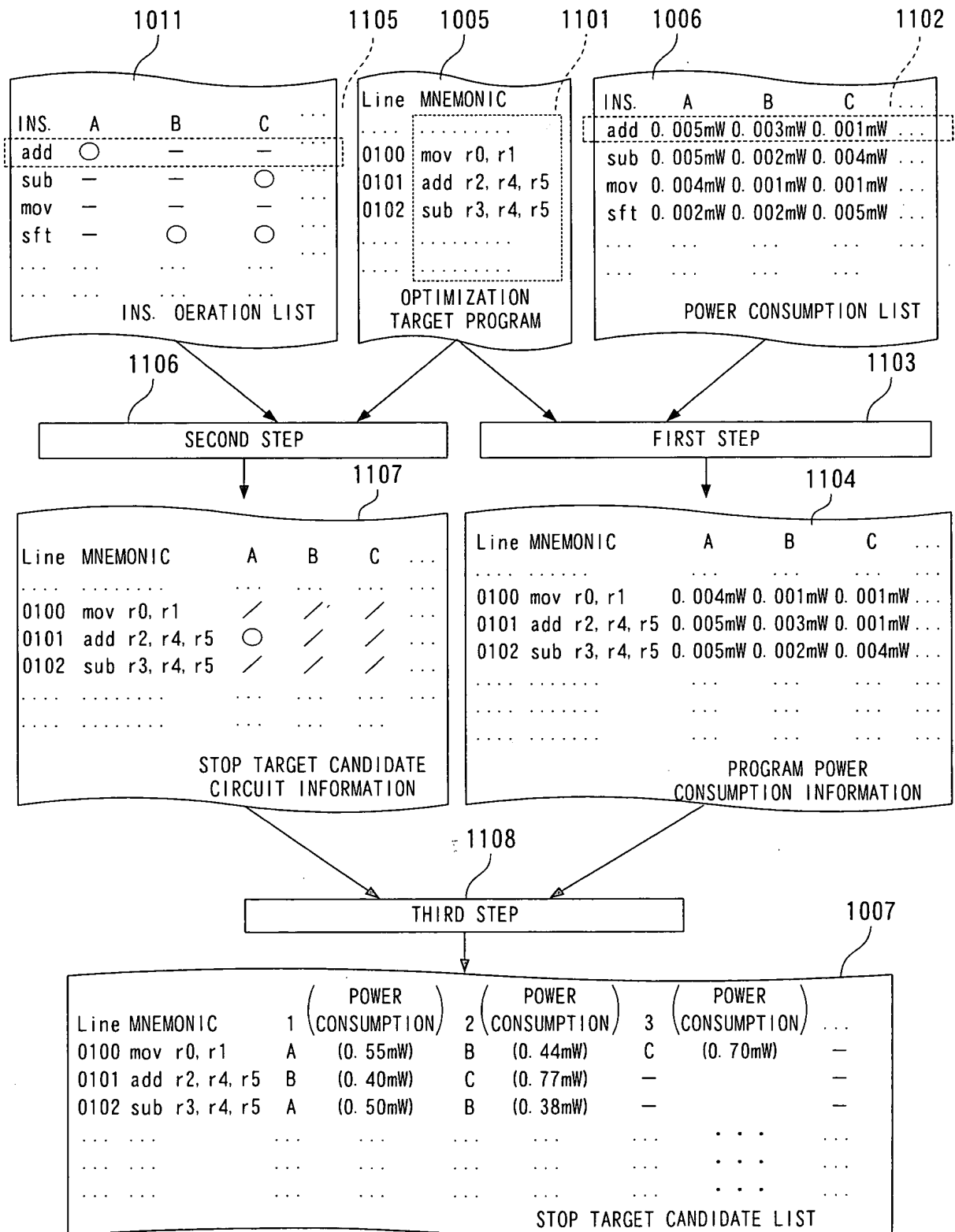


FIG. 14

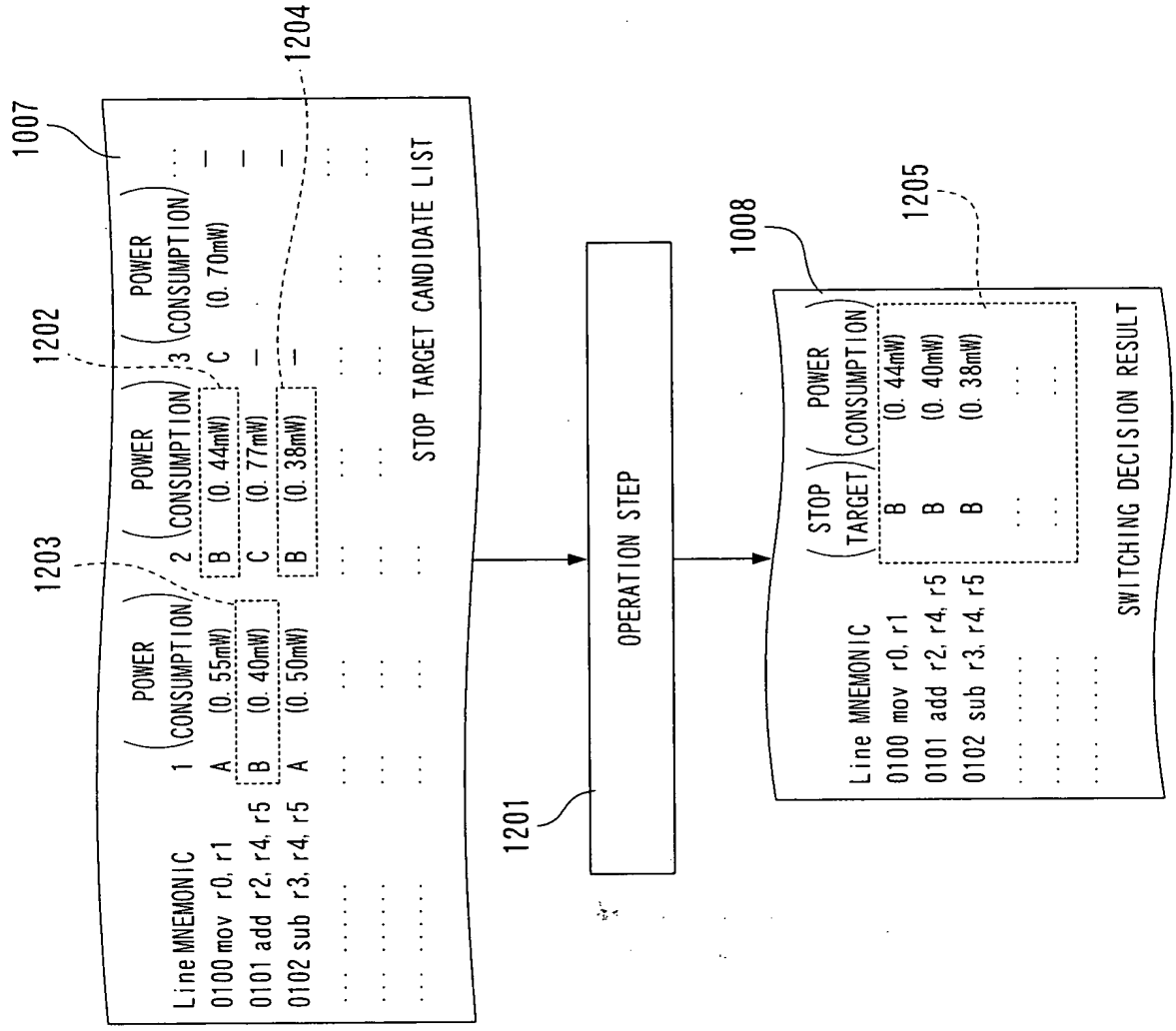


FIG. 15

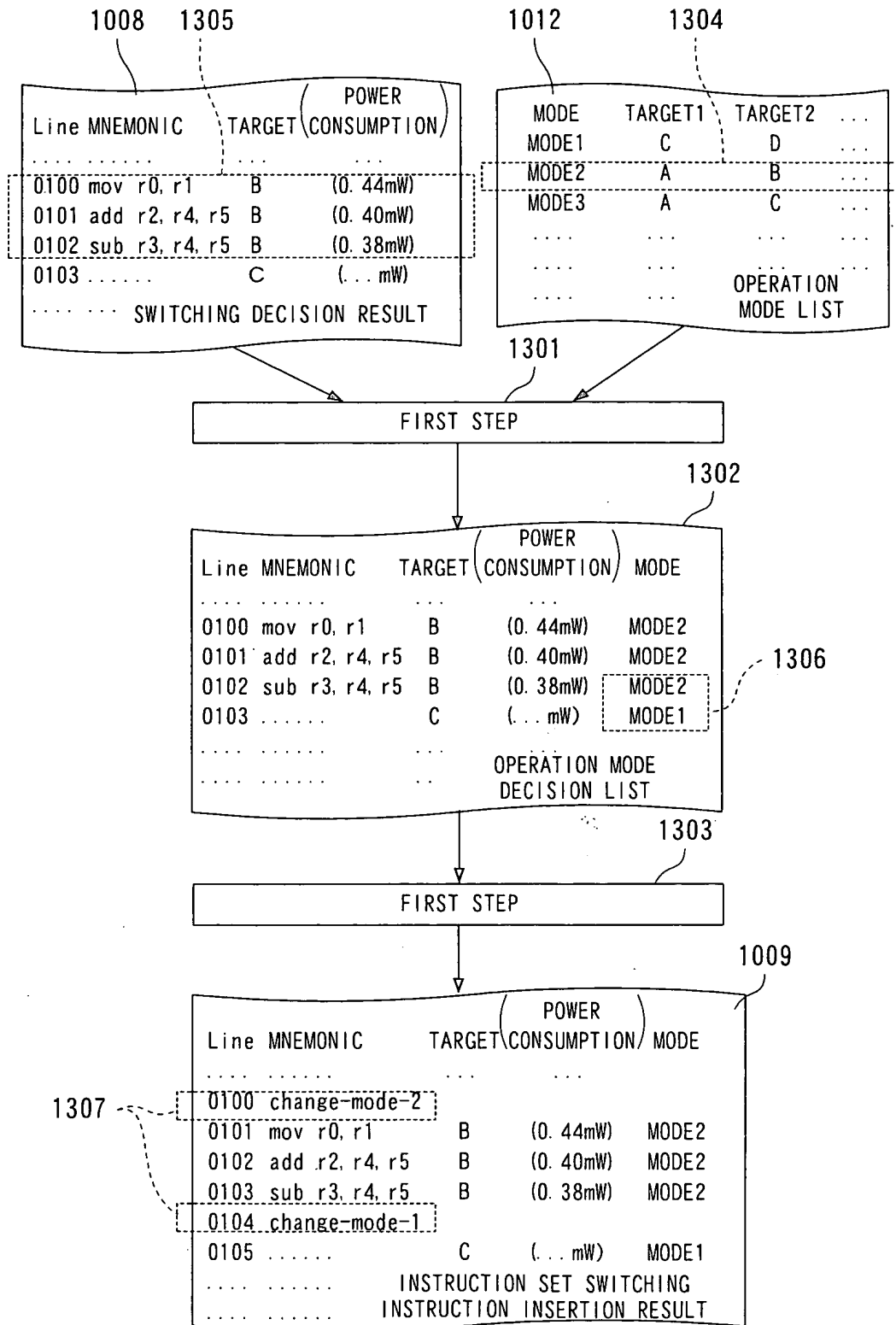


FIG. 16

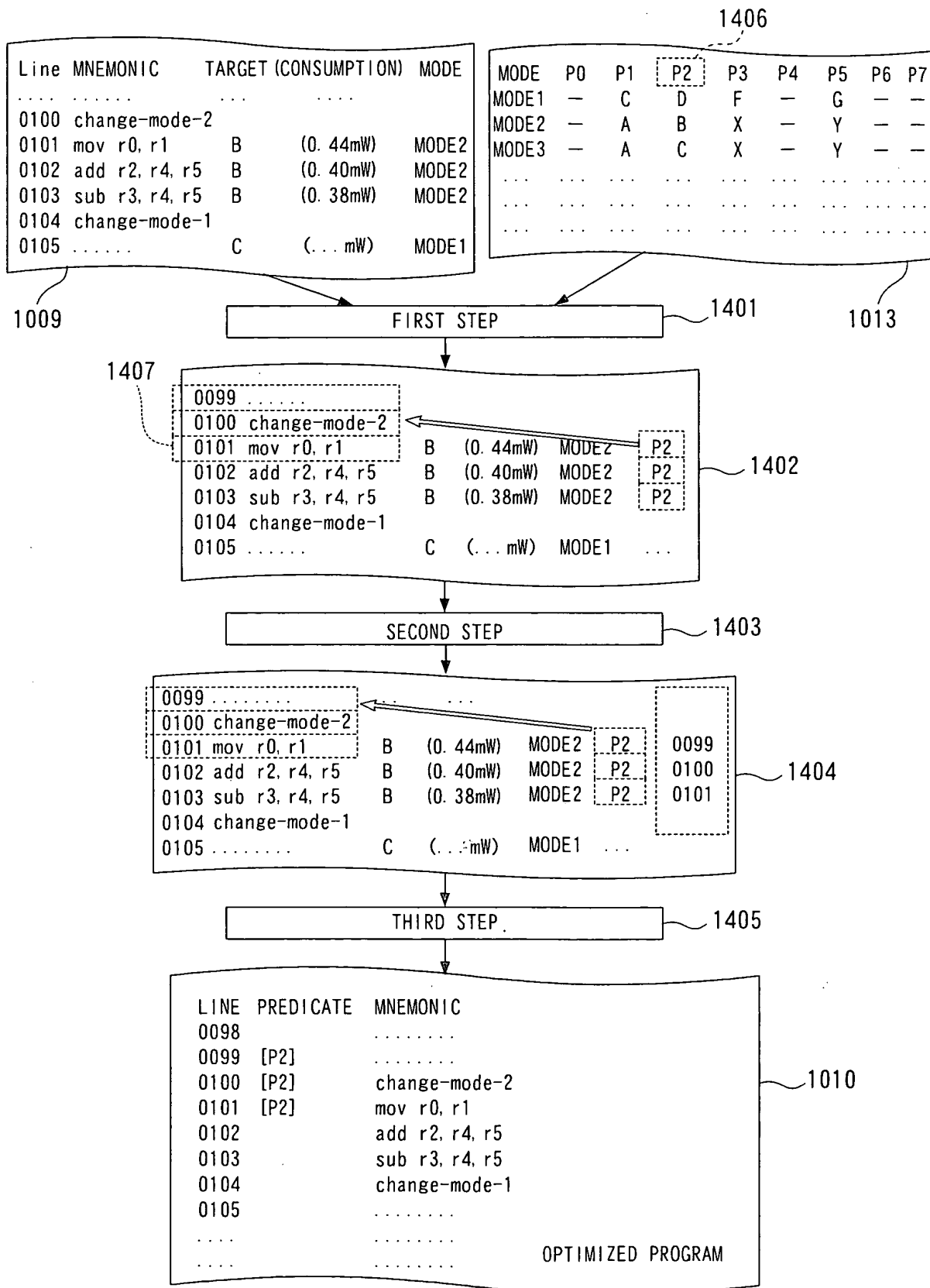


FIG. 17

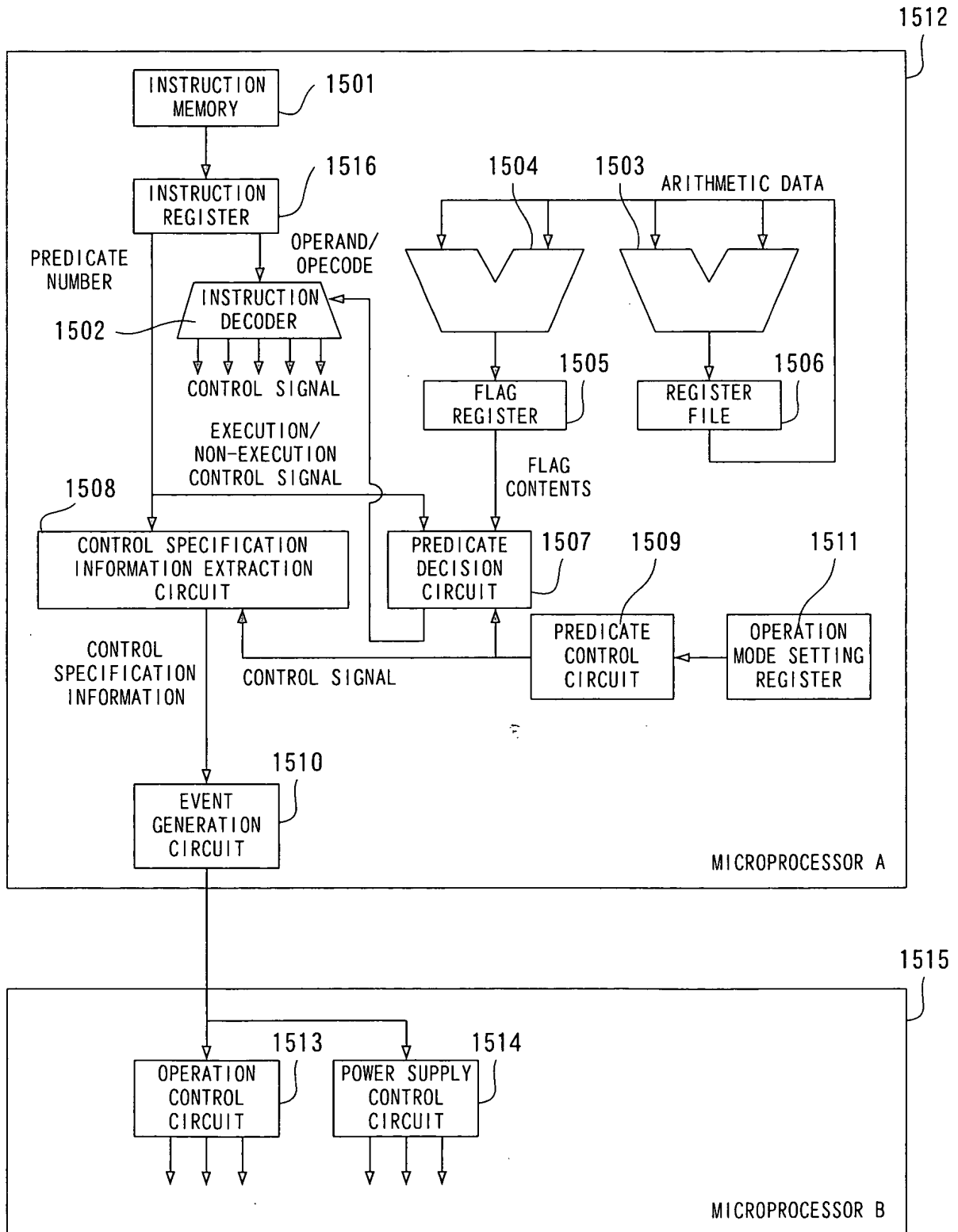


FIG. 18

PIPELINE AT [n-5]
(MICROPROCESSOR A)

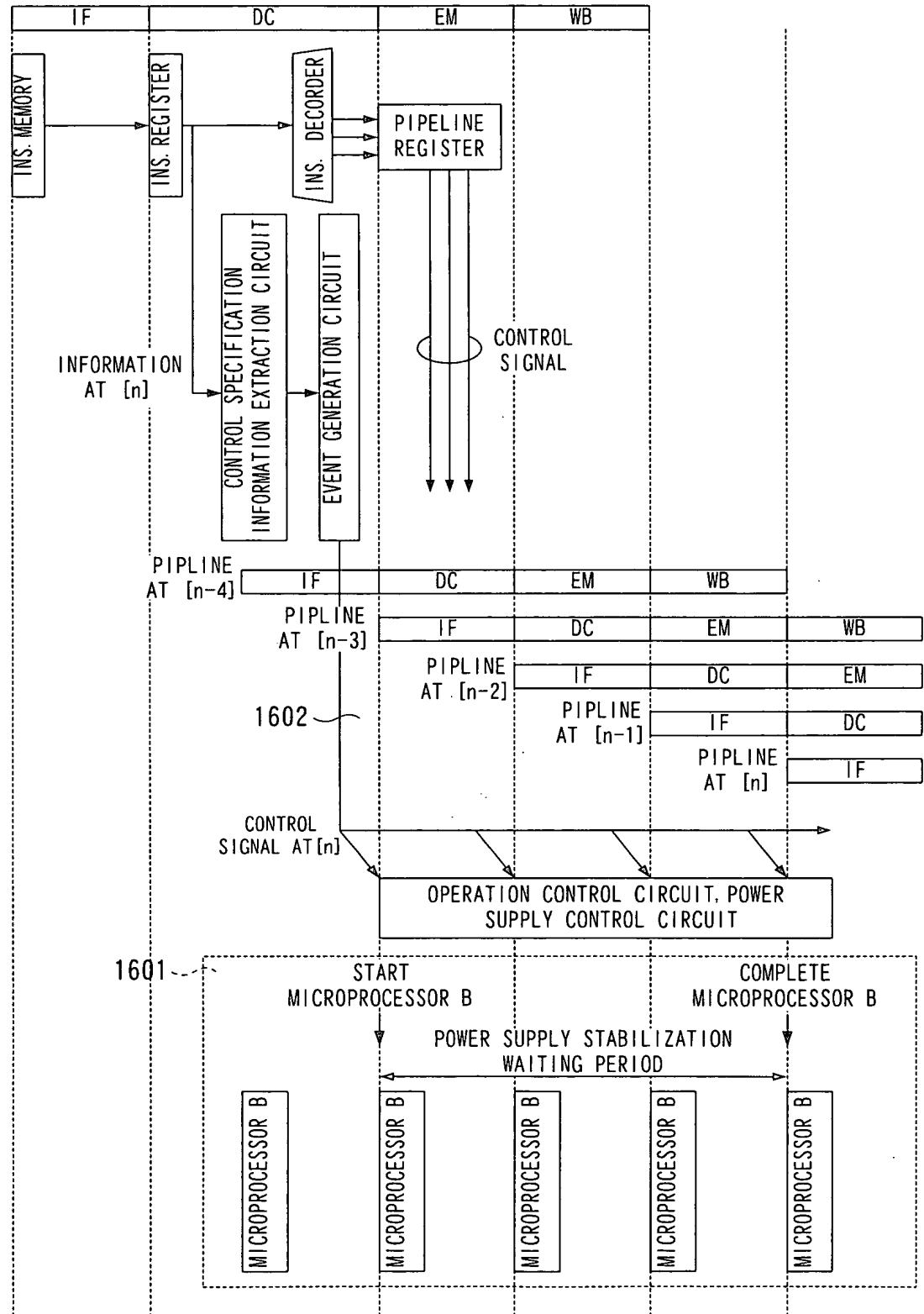


FIG. 19

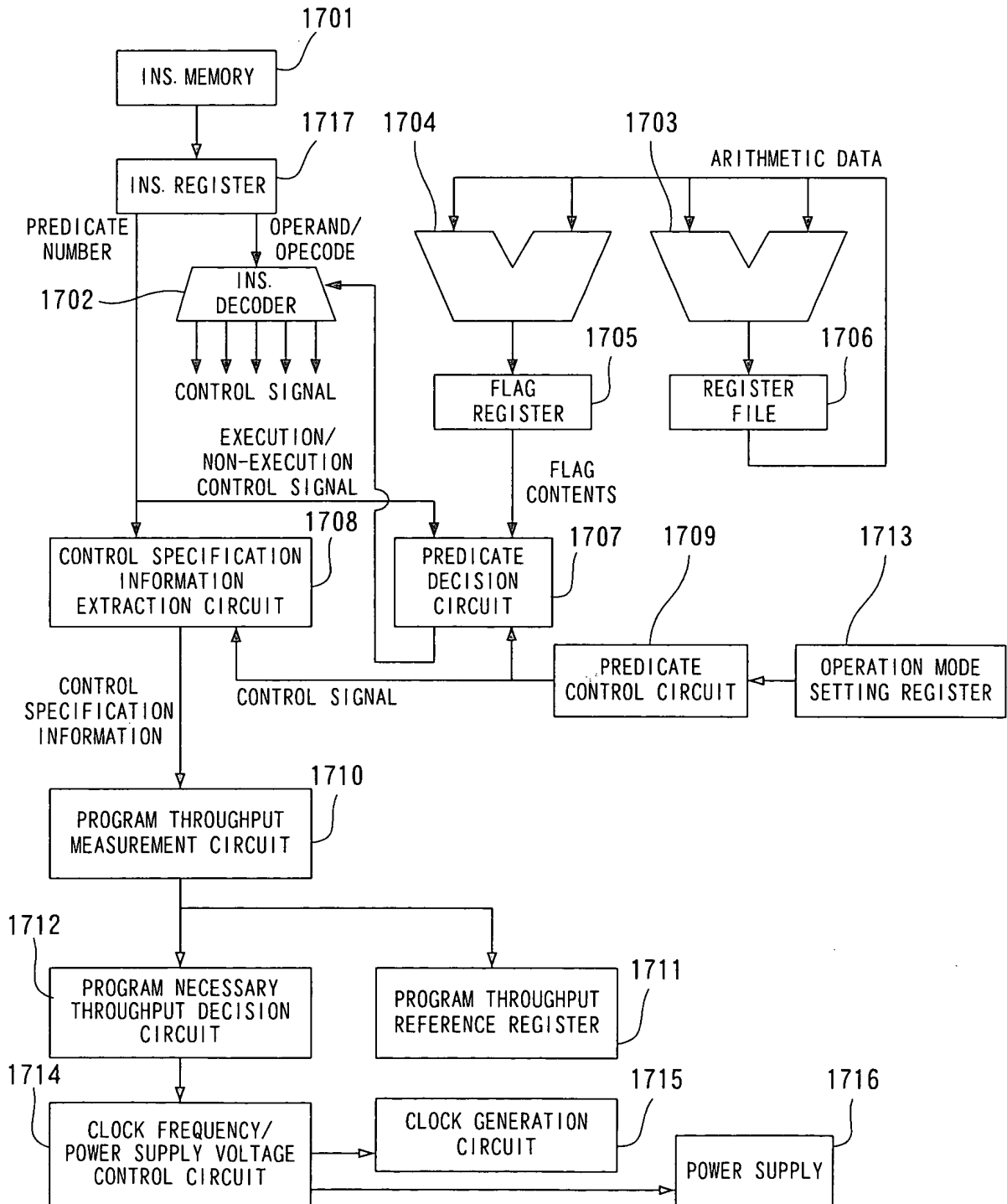


FIG. 20

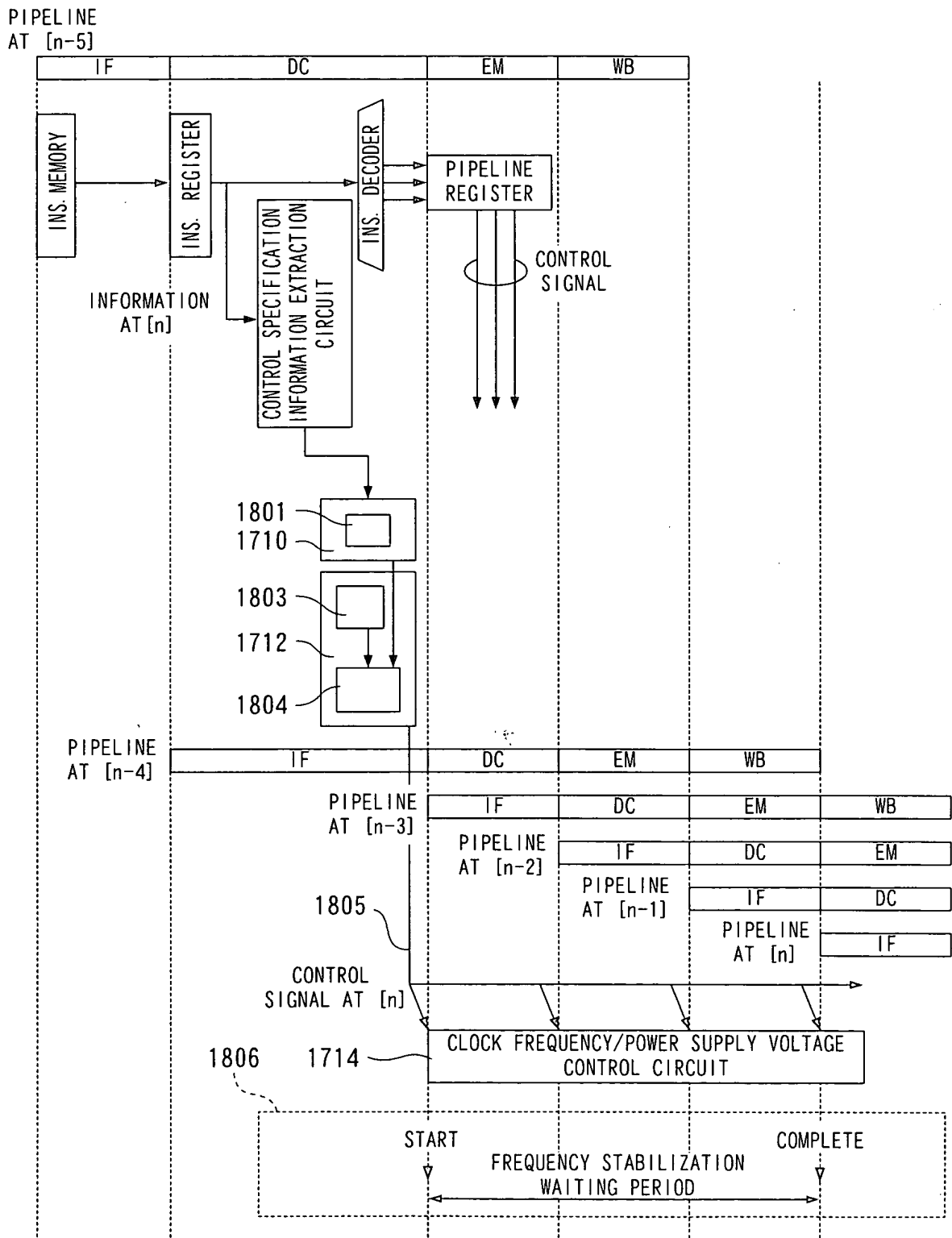


FIG. 21A

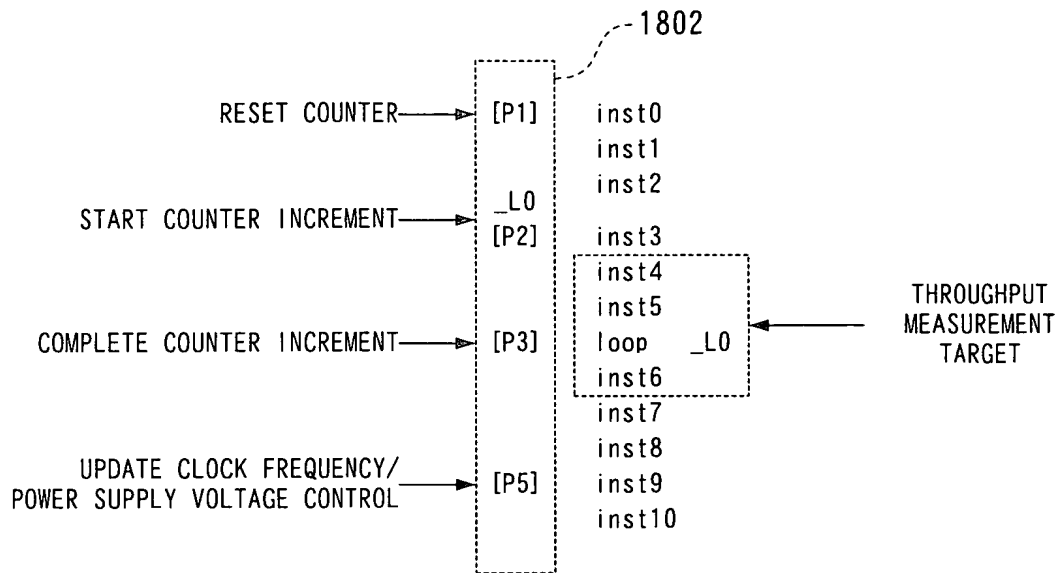


FIG. 21B

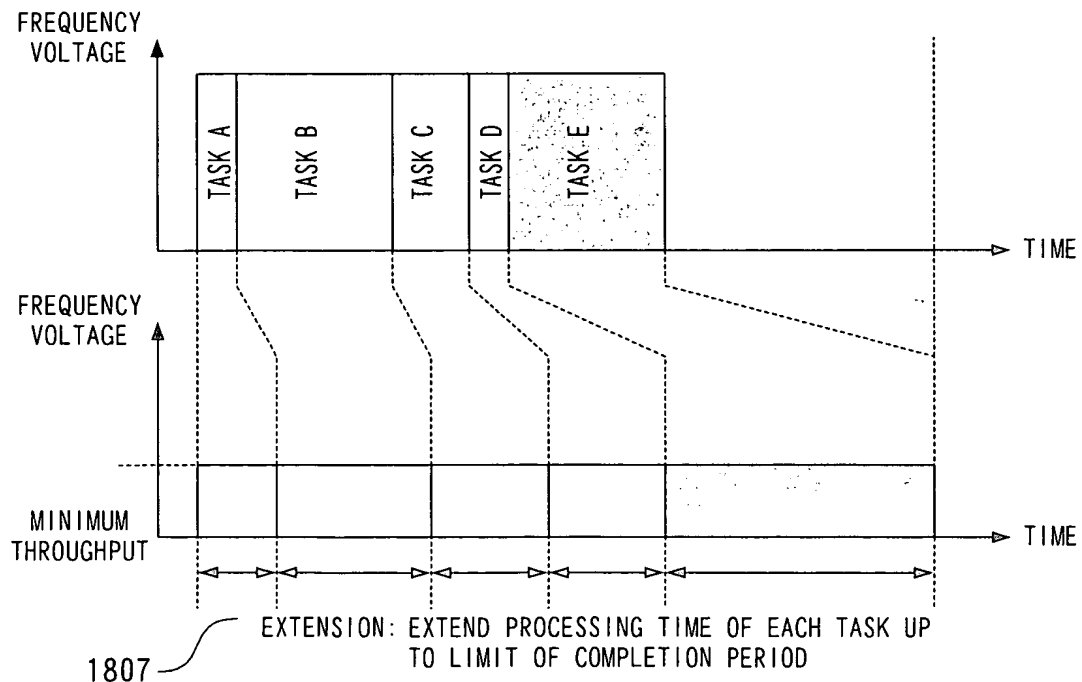
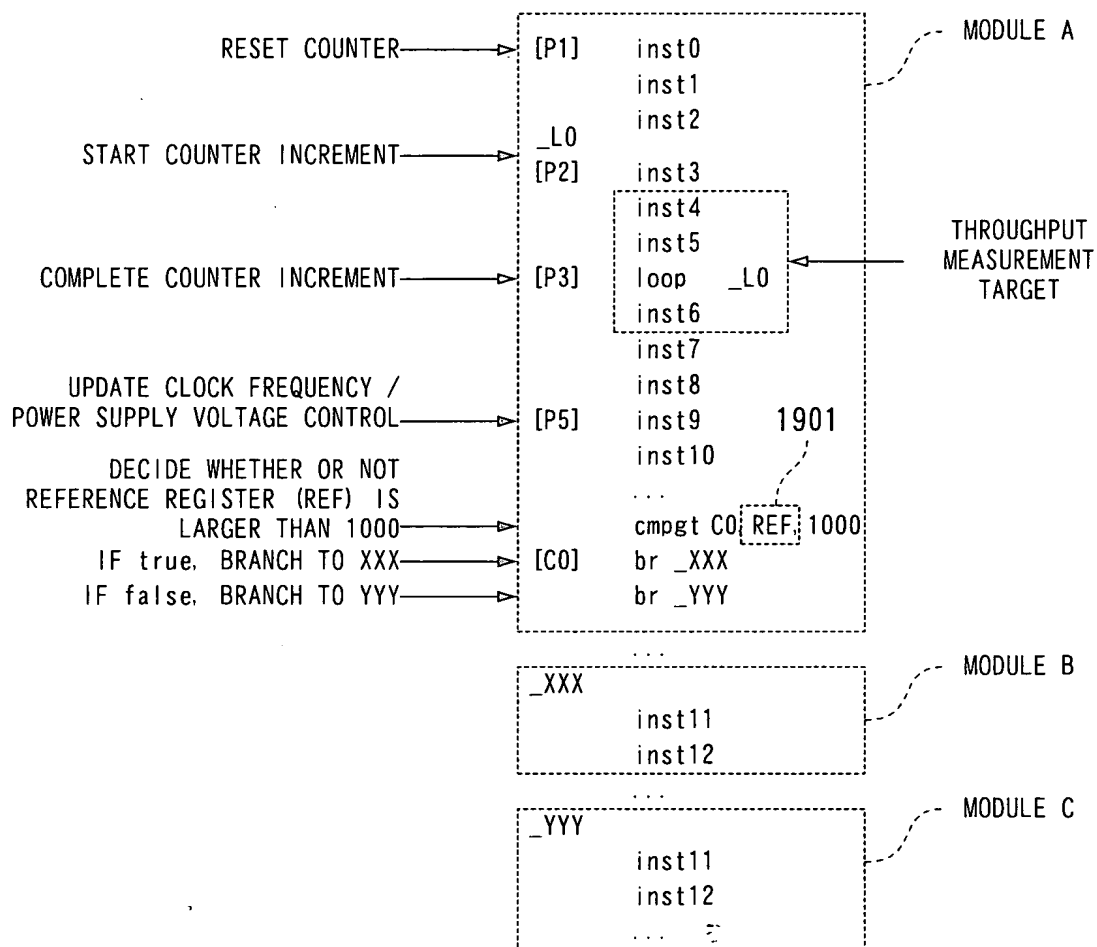


FIG. 22B



PROGRAM FOR DECIDING THROUGHPUT

```
[C0]    inst0
[C1]    inst1
[C1]    inst2
[C2]    inst3
[C2]    inst4
[C0]    inst5
[C0]    inst6
[C3]    inst7
[C3]    inst8
[C5]    inst9
[C5]    inst10
```

Diagram illustrating a memory layout for throughput measurement targets. The layout consists of a sequence of memory blocks, each containing a label and an instance name. Arrows indicate the mapping from these blocks to the throughput measurement targets.

Block Label	Instance Name	Throughput Measurement Target
[C0]	inst0	
[P1]	inst1	THROUGHPUT MEASUREMENT TARGET
[C1]	inst2	
[P2]	inst3	THROUGHPUT MEASUREMENT TARGET
[P2]	inst4	THROUGHPUT MEASUREMENT TARGET
[P0]	inst5	THROUGHPUT MEASUREMENT TARGET
[P0]	inst6	THROUGHPUT MEASUREMENT TARGET
[C3]	inst7	
[P3]	inst8	THROUGHPUT MEASUREMENT TARGET
[P5]	inst9	THROUGHPUT MEASUREMENT TARGET
[C5]	inst10	